

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KIM ET AL.	
		Examiner Linh T. Nguyen	Art Unit 2627	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0156291	08-2004	Heemskerk et al.	369/053.34
*	B	US-2003/0179678	09-2003	Kobayashi, Shoei	369/59.25
*	C	US-2005/0099934	05-2005	Kondo et al.	369/275.4
*	D	US-2005/0030854	02-2005	Lee et al.	369/047.22
*	E	US-2003/0107970	06-2003	Suh, Sang Woon	369/59.25
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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